

Search Notes 	Application/Control No.	Applicant(s)/Patent Under Reexamination
	10609493	SHINOTUKA ET AL.
	Examiner Carter, Aaron W	Art Unit 2624

Notes	Date	Examiner
EAST Text Search (USPAT, PGPUB, IBM, EPO) See Search History Printout	10/24/06	AWC
Inventor Name Search (See PALM Search History Printout, Check Marks Indicate Applications Considered)	10/24/06	AWC
IEEE Text and Author Search, See Search History Printout	10/24/06	AWC
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382	274	10/24/06	AWC
250	205	10/24/06	AWC
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348	251	10/24/06	AWC
358	461	10/24/06	AWC

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